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Attn: DO/US

IN THE UNITED STATES DESIGNATED OFFICE (DO/US)

Applicant(s): Rouviere et al.
International Appl. No.: PCT/FR04/01877 **IAP20 Rec'd PCT/PTO 18 JAN 2006**
International Filing Date: July 16, 2004
Title: METHOD FOR MEASURING PHYSICAL PARAMETERS OF
AT LEAST ONE MICROMETRIC OR NANOMETRIC
DIMENSIONAL PHASE IN A COMPOSITE SYSTEM

Docket No.: 033339/306516
Customer No.: 00826

Mail Stop PCT
Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

**PRELIMINARY AMENDMENT
37 CFR § 1.115**

Sir:

Please enter this Preliminary Amendment before calculating the claim fee and amend the above-identified application as follows:

Amendments to the Claims are reflected in the listing of claims beginning on page 2 of this paper.

Remarks begin on page 5 of this paper.